

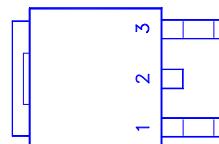
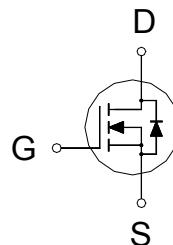
**NIKO-SEM**
**N-Channel Enhancement Mode  
Field Effect Transistor**
**P2806BD**

TO-252

Halogen-Free &amp; Lead-Free

**PRODUCT SUMMARY**

$V_{(BR)DSS}$	$R_{DS(ON)}$	$I_D$
60V	28mΩ	30A



1. GATE
2. DRAIN
3. SOURCE

**ABSOLUTE MAXIMUM RATINGS ( $T_A = 25^\circ\text{C}$  Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNITS
Gate-Source Voltage		$V_{GS}$	$\pm 20$	V
Continuous Drain Current	$T_C = 25^\circ\text{C}$	$I_D$	30	A
	$T_C = 100^\circ\text{C}$		19	
Pulsed Drain Current <sup>1</sup>		$I_{DM}$	100	
Avalanche Current		$I_{AS}$	30	
Avalanche Energy	$L = 0.1\text{mH}$	$E_{AS}$	43	mJ
Power Dissipation	$T_C = 25^\circ\text{C}$	$P_D$	50	W
	$T_C = 100^\circ\text{C}$		20	
Operating Junction & Storage Temperature Range		$T_j, T_{stg}$	-55 to 150	°C

**THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$	2.5	40	°C / W
Junction-to-Ambient	$R_{\theta JA}$			

<sup>1</sup>Pulse width limited by maximum junction temperature.
**ELECTRICAL CHARACTERISTICS ( $T_J = 25^\circ\text{C}$ , Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$	60			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	1	1.5	3	
Gate-Body Leakage	$I_{GSS}$	$V_{DS} = 0\text{V}, V_{GS} = \pm 20\text{V}$			$\pm 250$	nA
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 48\text{V}, V_{GS} = 0\text{V}$			1	$\mu\text{A}$
		$V_{DS} = 40\text{V}, V_{GS} = 0\text{V}, T_J = 125^\circ\text{C}$			10	
On-State Drain Current <sup>1</sup>	$I_{D(\text{ON})}$	$V_{DS} = 10\text{V}, V_{GS} = 10\text{V}$	100			A
Drain-Source On-State Resistance <sup>1</sup>	$R_{DS(\text{ON})}$	$V_{GS} = 4.5\text{V}, I_D = 12\text{A}$		28	38	$\text{m}\Omega$
		$V_{GS} = 10\text{V}, I_D = 20\text{A}$		22.3	28	

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Forward Transconductance <sup>1</sup>	$g_{fs}$	$V_{DS} = 5V, I_D = 20A$		25		S
<b>DYNAMIC</b>						
Input Capacitance	$C_{iss}$	$V_{GS} = 0V, V_{DS} = 25V, f = 1MHz$		1500		pF
Output Capacitance	$C_{oss}$			168		
Reverse Transfer Capacitance	$C_{rss}$			106		
Gate Resistance	$R_g$	$V_{GS} = 0V, V_{DS} = 0V, f = 1MHz$		1.3		$\Omega$
Total Gate Charge <sup>2</sup>	$Q_g$	$V_{DS} = 30V, V_{GS} = 10V,$ $I_D = 20A$		27.4		nC
Gate-Source Charge <sup>2</sup>	$Q_{gs}$			6.1		
Gate-Drain Charge <sup>2</sup>	$Q_{gd}$			5.8		
Turn-On Delay Time <sup>2</sup>	$t_{d(on)}$	$V_{DD} = 30V,$ $I_D \geq 20A, V_{GS} = 10V, R_{GEN} = 6\Omega$		8		nS
Rise Time <sup>2</sup>	$t_r$			6		
Turn-Off Delay Time <sup>2</sup>	$t_{d(off)}$			29		
Fall Time <sup>2</sup>	$t_f$			6		
<b>SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (<math>T_J = 25^\circ C</math>)</b>						
Continuous Current	$I_S$				30	A
Forward Voltage <sup>1</sup>	$V_{SD}$	$I_F = 20 A, V_{GS} = 0V$			1.3	V
Reverse Recovery Time	$t_{rr}$	$I_F = 20A, di_F/dt = 100A/\mu s$		41		nS
Reverse Recovery Charge	$Q_{rr}$			46		nC

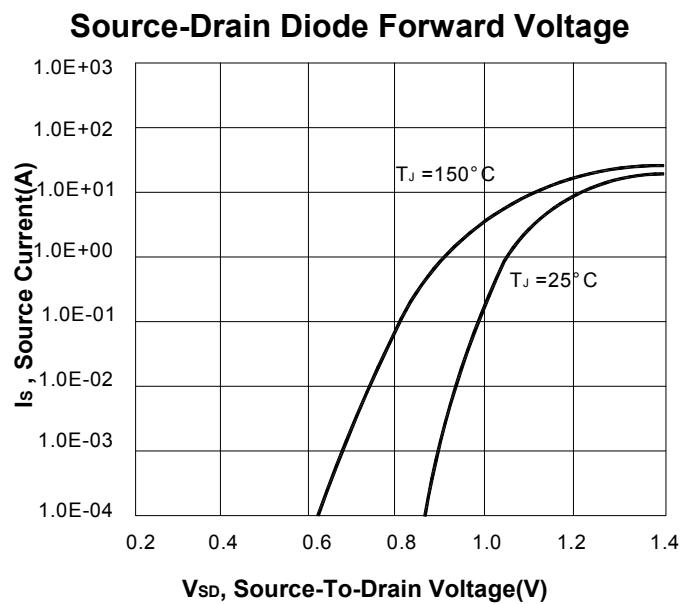
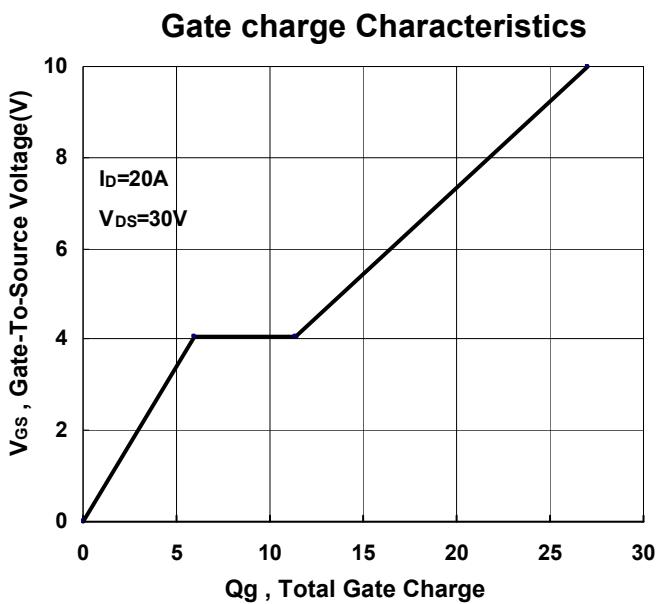
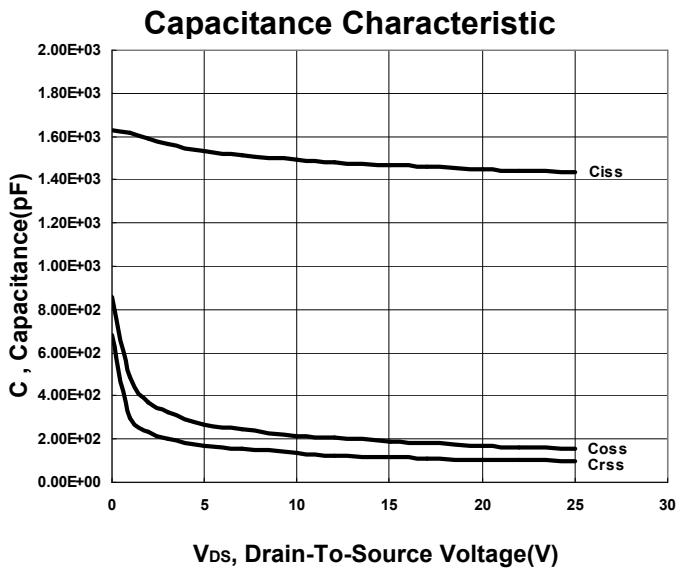
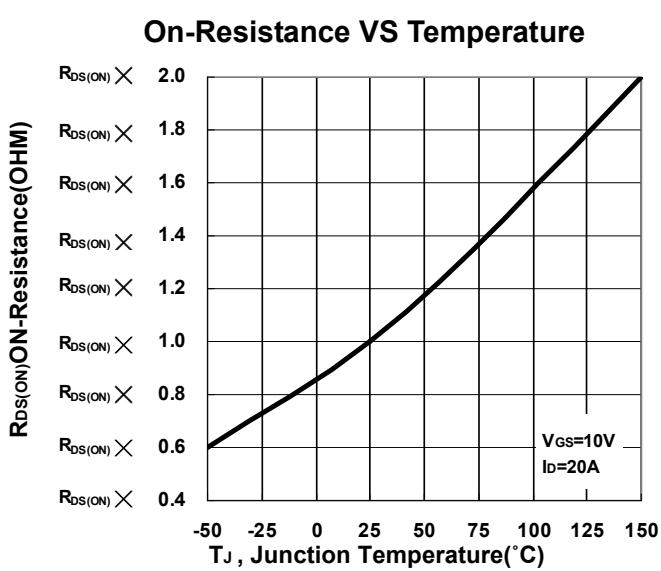
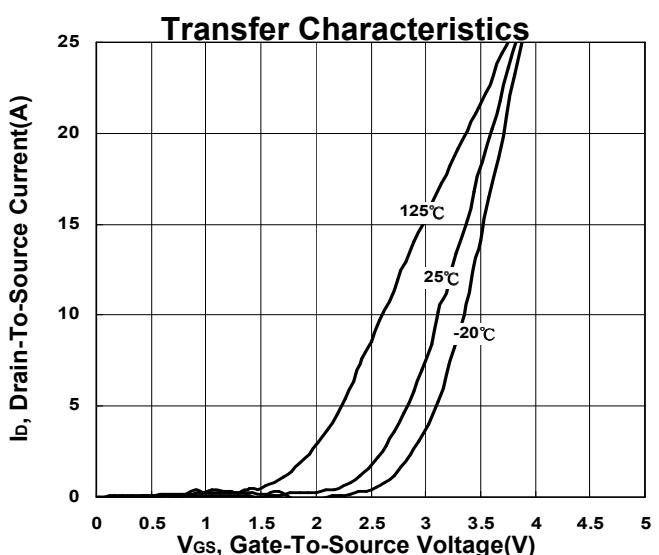
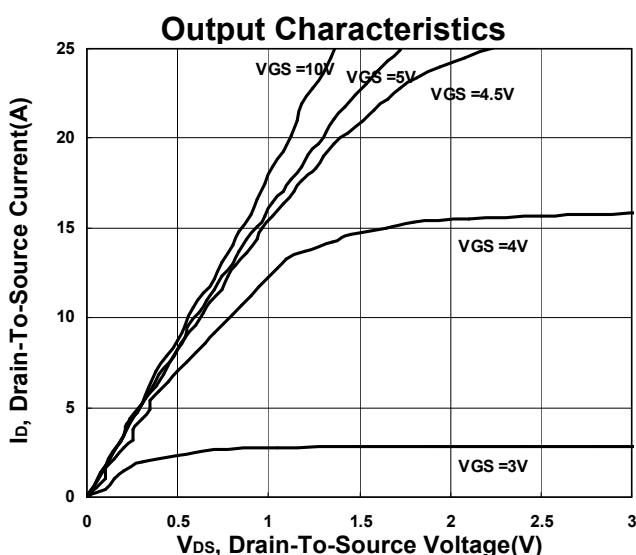
<sup>1</sup>Pulse test : Pulse Width  $\leq 300 \mu sec$ , Duty Cycle  $\leq 2\%$ .<sup>2</sup>Independent of operating temperature.

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